

JEOL JIB 4700 FIB-SEM

JIB-4700F Multi Beam System with Energy Dispersive X-ray spectroscopy (EDS) and Electron Backscatter Diffraction (EBSD) can be used in morphological observations and elemental and crystallographic analyses of various specimen.



JEOL JEM 2100















THIN FILM XRD

GIXRD, HRXRD, RSM, XRR, & COUPLED 2THETA-OMEGA



BULK & POWDER XRD

Multipurpose X-ray diffraction (XRD) system for analysis of powders solids

and thin film specimens





LAMINAR AIR FLOW

CABINET



UV VIS



CUTTING MACHINES



ABRASIVE CUTTING MACHINE



GRINDING & POLISHING MACHINE



AUTOMATIC TWIN JET POLISHING MACHINE



DILATOMETER



DSC-TGA



ELCETRO POLISHING



ELECTRO SPARK COATING



FUME HOOD



GOLD SPUTTERING



















MAGNETRON SPUTTERING SYSTEM WITH RF AND DC CAPABILITY









TUBULAR FURNACE





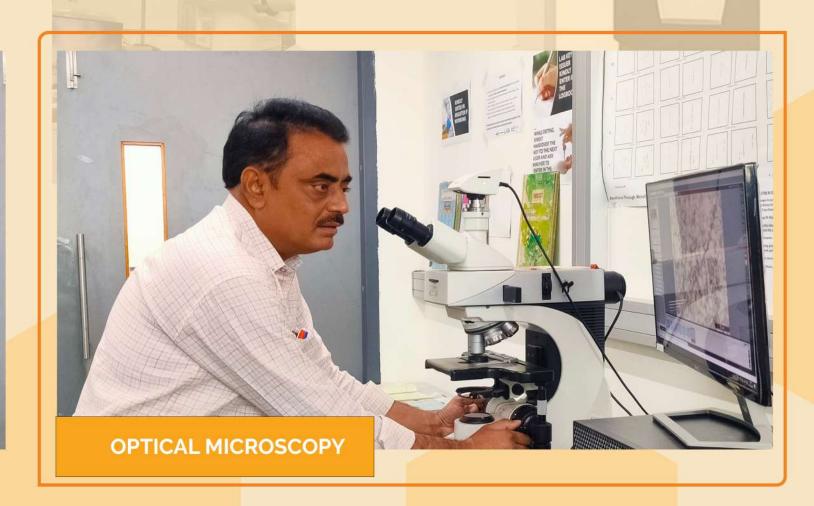






BRINELL HARDNESS TESTER



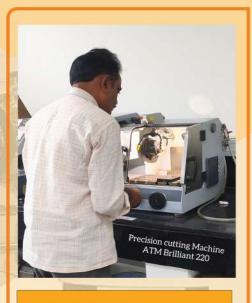




WELDING MACHINE



MICRO HARDNESS TESTER



PRECESION CUTTING MACHINE



DIAMOND WIRE SAW



JAR MIXTURE



LOW SPEED SAW